

Notice of References Cited	Application/Control No. 10/656,013	Applicant(s)/Patent Under Reexamination MITRA ET AL.	
	Examiner Phung My Chung	Art Unit 2117	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,032,148 B2	04-2006	Wang et al.	714/729
*	B	US-5,436,912 A	07-1995	Lustig, Bernhard	714/719
*	C	US-6,373,758	04-2002	Hughes et al.	365/200
*	D	US-6,259,637	07-2001	Wood et al.	365/200
*	E	US-4,628,509	12-1986	Kawaguchi, Ikuo	714/711
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Mitra et al "AN Efficient Response Compaction Technique For Test Cost Reduction" IEEE, 04//2002, paper 11.2, pages 311-320.
	V	Patel et al "Application of Saluja-Karpovsky Compactors to Test Responses with Many Unknowns" . 07/16/2003, Proceedings of the 21 st IEEE VLSI Test Symposium (VTS'03) total 6pages.
)	W	Rajski et al "Convolutional Compaction of Test Responses" ITC International Test Conference, IEEE copyright 08/06/2003, paper 29.3, pages 745-754.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.